## Notice of References Cited Application/Control No. 10/705,239 Applicant(s)/Patent Under Reexamination TOGAWA ET AL. Examiner Dillon Durnford-Geszvain Applicant(s)/Patent Under Reexamination TOGAWA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,212,555	05-1993	Stoltz, Richard A	348/203
*	В	US-6,464,363	10-2002	Nishioka et al.	359/846
*	С	US-6,437,925	08-2002	Nishioka, Kimihiko	359/726
*	D	US-2004/0012710	01-2004	Yaji et al.	348/362
*	Е	US-2002/0118464	08-2002	Nishioka et al.	359/642
*	F	US-2002/0136150	09-2002	Mihara et al.	369/125
*	G	US-2006/0142877	06-2006	Solomon, Mark B.	700/011
*	н	US-2003/0107789	06-2003	Hishioka, Kimihiko	359/223
*	1	US-2004/0012683	01-2004	Yamasaki et al.	348/208.1
*	J	US-2005/0212946	09-2005	Mikami, Kazuo	348/335
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
	R		4			
	s					
	Т					

## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.